

CMOS Analog Switches

The HI-300 thru HI-307 series of switches are monolithic devices fabricated using CMOS technology and the Intersil dielectric isolation process. These switches feature break before-make switching, (HI-301, HI-303 and HI-307 only), low and nearly constant ON resistance over the full analog signal range, and low power dissipation, (a few mW for the HI-300 thru HI-303, a few hundred mW for the HI-307).

The HI-300 thru HI-303 are TTL compatible and have a logic "0" condition with an input less than 0.8V and a logic "1" condition with an input greater than 4V. The HI-307 switches are CMOS compatible and have a low state with an input less than 3.5V and a high state with an input greater than 11V. (See pinouts for switch conditions with a logic "1" input.)

Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
HI1-0300-2	-55 to 125	14 Ld CERDIP	F14.3
HI9P0301-5	0 to 75	14 Ld SOIC	M14.15
HI1-0303-2	-55 to 125	14 Ld CERDIP	F14.3
HI1-0303-5	0 to 75	14 Ld CERDIP	F14.3
HI3-0303-5	0 to 75	14 Ld PDIP	E14.3
HI9P0303-5	0 to 75	14 Ld SOIC	M14.15
HI9P0303-9	-40 to 85	14 Ld SOIC	M14.15
HI1-0307-5	0 to 75	14 Ld CERDIP	F14.3

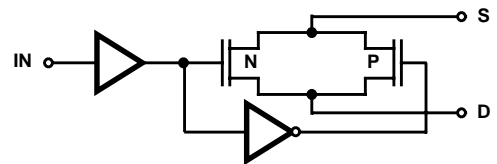
Features

- Analog Signal Range ($\pm 15V$ Supplies) $\pm 15V$
- Low Leakage at 25°C 40pA
- Low Leakage at 125°C 1nA
- Low On Resistance at 25°C 35 Ω
- Break-Before-Make Delay 60ns
- Charge Injection 30pC
- TTL, CMOS Compatible
- Symmetrical Switch Elements
- Low Operating Power (Typ for HI-300 thru HI-303) . . 1.0mW

Applications

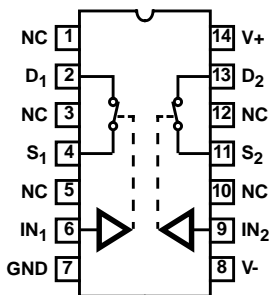
- Sample and Hold (i.e., Low Leakage Switching)
- Op Amp Gain Switching (i.e., Low On Resistance)
- Portable, Battery Operated Circuits
- Low Level Switching Circuits
- Dual or Single Supply Systems

Functional Diagram



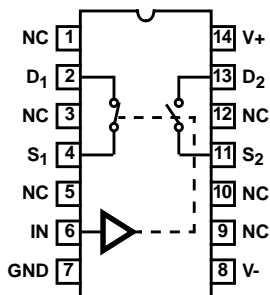
Pinouts Switch States Shown For A Logic "1" Input

DUAL SPST HI-300 (CERDIP) TOP VIEW



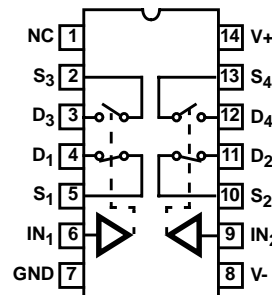
LOGIC	SWITCHES
0	OFF
1	ON

SPST HI-301 (SOIC) TOP VIEW



LOGIC	SW1	SW2
0	OFF	ON
1	ON	OFF

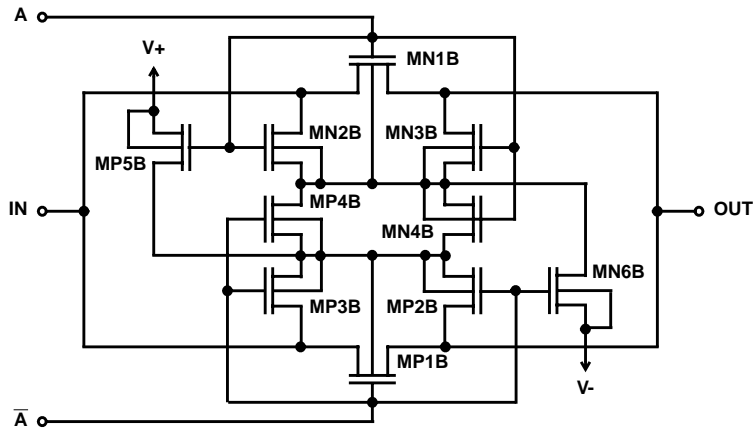
DUAL SPDT HI-303 (PDIP, CERDIP, SOIC) HI-307 (CERDIP) TOP VIEW



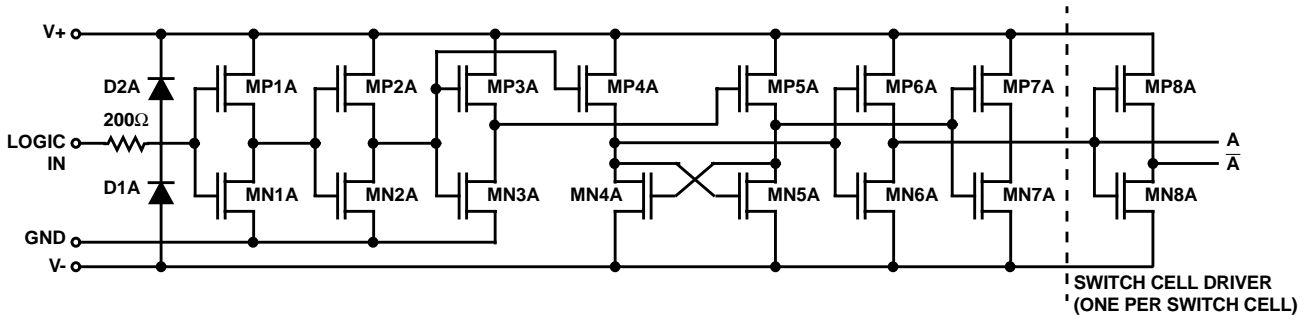
LOGIC	SW1	SW2	SW3	SW4
0	OFF	OFF	ON	ON
1	ON	ON	OFF	OFF

Schematic Diagrams

SWITCH CELL



DIGITAL INPUT BUFFER AND LEVEL SHIFTER



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HI-300 thru HI-307

Absolute Maximum Ratings

Voltage Between Supplies (V+ to V-)	44V (±22V)
Digital Input Voltage (V+) +4V to (V-) -4V	
Analog Input Voltage (V+) +1.5V to (V-) -1.5V	
Typical Derating Factor	1.5mA/MHz Increase in ICCOP
ESD Classification	Class 1

Operating Conditions

Temperature Range	
HI-3XX-2	-55°C to 125°C
HI-3XX-5	0°C to 75°C
HI-3XX-9	-40°C to 85°C

Thermal Information

Thermal Resistance (Typical, Note 1)	θ_{JA} (°C/W)	θ_{JC} (°C/W)
CERDIP Package	95	40
PDIP Package	100	N/A
SOIC Package	120	N/A
Maximum Junction Temperature		
Ceramic Packages		175°C
Plastic Packages		150°C
Maximum Storage Temperature Range		-65°C to 150°C
Maximum Lead Temperature (Soldering 10s)		300°C
(SOIC - Lead Tips Only)		

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

- θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications Supplies = +15V, -15V; V_{IN} = Logic Input. HI-300 thru HI-303: V_{IN} - for Logic "1" = 4V, for Logic "0" = 0.8V. HI-307: V_{IN} - for Logic "1" = 11V, for Logic "0" = 3.5V, Unless Otherwise Specified

PARAMETER	TEMP (°C)	-2			-5, -9			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
DYNAMIC CHARACTERISTICS								
Switch ON Time, t_{ON} (Note 13)	25	-	210	300	-	210	300	ns
Switch OFF Time, t_{OFF} (Note 13)	25	-	160	250	-	160	250	ns
Switch ON Time, t_{ON} (Note 14)	25	-	160	250	-	160	250	ns
Switch OFF Time, t_{OFF} (Note 14)	25	-	100	150	-	100	150	ns
Break-Before-Make Delay, t_{OPEN} (Note 15)	25	-	60	-	-	60	-	ns
Charge Injection Voltage, ΔV (Note 7)	25	-	3	-	-	3	-	mV
OFF Isolation (Note 6)	25	-	60	-	-	60	-	dB
Input Switch Capacitance, $C_{S(OFF)}$	25	-	16	-	-	16	-	pF
Output Switch Capacitance, $C_{D(OFF)}$	25	-	14	-	-	14	-	pF
Output Switch Capacitance, $C_{D(ON)}$	25	-	35	-	-	35	-	pF
Digital Input Capacitance, C_{IN}	25	-	5	-	-	5	-	pF
DIGITAL INPUT CHARACTERISTICS								
Input Low Level, V_{INL} (Note 13)	Full	-	-	0.8	-	-	0.8	V
Input High Level, V_{INH} (Note 13)	Full	4	-	-	4	-	-	V
Input Low Level, V_{INL} (Note 14)	Full	-	-	3.5	-	-	3.5	V
Input High Level, V_{INH} (Note 14)	Full	11	-	-	11	-	-	V
Input Leakage Current (Low), I_{INL} (Note 5)	Full	-	-	1	-	-	1	μA
Input Leakage Current (High), I_{INH} (Note 5)	Full	-	-	1	-	-	1	μA
ANALOG SWITCH CHARACTERISTICS								
Analog Signal Range	Full	-15	-	+15	-15	-	+15	V
ON Resistance, r_{ON} (Note 2)	25	-	35	50	-	35	50	Ω
	Full	-	40	75	-	40	75	Ω
OFF Input Leakage Current, $I_{S(OFF)}$ (Note 3)	25	-	0.04	1	-	0.04	5	nA
	Full	-	1	100	-	0.2	100	nA
OFF Output Leakage Current, $I_{D(OFF)}$ (Note 3)	25	-	0.04	1	-	0.04	5	nA
	Full	-	1	100	-	0.2	100	nA
ON Leakage Current, $I_{D(ON)}$ (Note 4)	25	-	0.03	1	-	0.03	5	nA
	Full	-	0.5	100	-	0.2	100	nA
POWER SUPPLY CHARACTERISTICS								
Current, I_+ (Notes 8, 13)	25	-	0.09	0.5	-	0.09	0.5	mA
	Full	-	-	1	-	-	1	mA

HI-300 thru HI-307

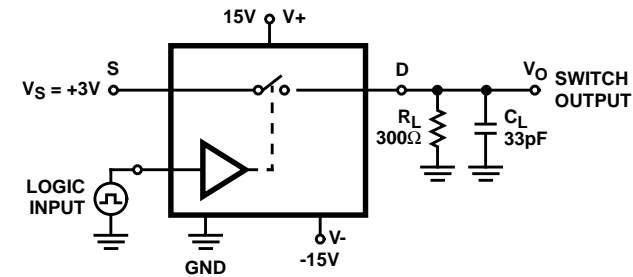
Electrical Specifications Supplies = +15V, -15V; V_{IN} = Logic Input. HI-300 thru HI-303: V_{IN} - for Logic "1" = 4V, for Logic "0" = 0.8V. HI-307: V_{IN} - for Logic "1" = 11V, for Logic "0" = 3.5V, Unless Otherwise Specified **(Continued)**

PARAMETER	TEMP (°C)	-2			-5, -9			UNITS
		MIN	TYP	MAX	MIN	TYP	MAX	
Current, I- (Notes 8, 13)	25	-	0.01	10	-	0.01	100	μ A
	Full	-	-	100	-	-	-	μ A
Current, I+ (Notes 9, 13)	25	-	0.01	10	-	0.01	100	μ A
	Full	-	-	100	-	-	-	μ A
Current, I- (Notes 9, 13)	25	-	0.01	10	-	0.01	100	μ A
	Full	-	-	100	-	-	-	μ A
Current, I+ (Notes 10, 14)	25	-	0.01	10	-	0.01	100	μ A
	Full	-	-	100	-	-	-	μ A
Current, I- (Notes 10, 14)	25	-	0.01	10	-	0.01	100	μ A
	Full	-	-	100	-	-	-	μ A
Current, I+ (Notes 11, 14)	25	-	0.01	10	-	0.01	100	μ A
	Full	-	-	100	-	-	-	μ A
Current, I- (Notes 11, 14)	25	-	0.01	10	-	0.01	100	μ A
	Full	-	-	100	-	-	-	μ A

NOTES:

2. $V_S = \pm 10V$, $I_{OUT} = \mp 10mA$. On resistance derived from the voltage measured across the switch under these conditions.
3. $V_S = \pm 14V$, $V_D = \mp 14V$.
4. $V_S = V_D = \pm 14V$.
5. The digital inputs are diode protected MOS gates and typical leakages of 1nA or less can be expected.
6. $V_S = 1V_{RMS}$, $f = 500kHz$, $C_L = 15pF$, $R_L = 1K$.
7. $V_S = 0V$, $C_L = 10nF$, Logic Drive = 5V pulse (HI-300 - 303), 15V pulse (HI-307). Switches are symmetrical; S and D may be interchanged. Charge Injection = $Q = C_L \times \Delta V$.
8. $V_{IN} = 4V$ (one input, all other inputs = 0V).
9. $V_{IN} = 0.8V$ (all inputs).
10. $V_{IN} = 15V$ (all inputs).
11. $V_{IN} = 0V$ (all inputs).
12. To drive from DTL/TTL circuits, pullup resistors to +5V supply are recommended.
13. HI-300 thru HI-303 only.
14. HI-307 only.
15. HI-301, HI-303, HI-307 only.

Test Circuits and Waveforms



SWITCH TYPE	V_{INH}
HI-300 thru HI-303	4V
HI-307	15V

FIGURE 1A. TEST CIRCUIT

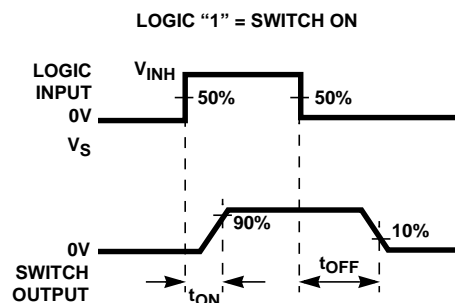


FIGURE 1B. MEASUREMENT POINTS

FIGURE 1. SWITCH t_{ON} AND t_{OFF}

Test Circuits and Waveforms (Continued)

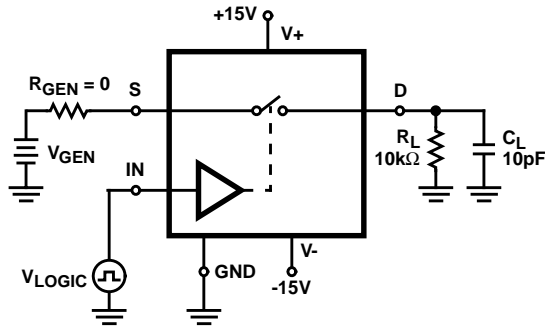


FIGURE 2A. TEST CIRCUIT

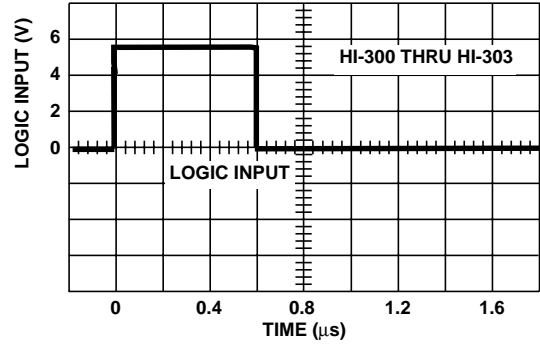


FIGURE 2B. TTL LOGIC INPUT

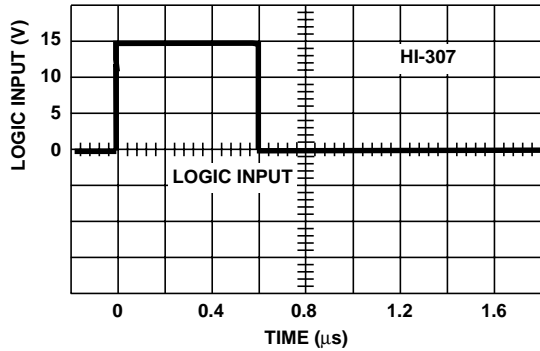


FIGURE 2C. CMOS LOGIC INPUT

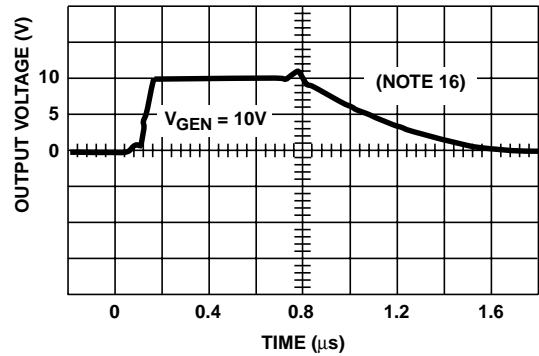


FIGURE 2D. $V_{ANALOG} = 10V$

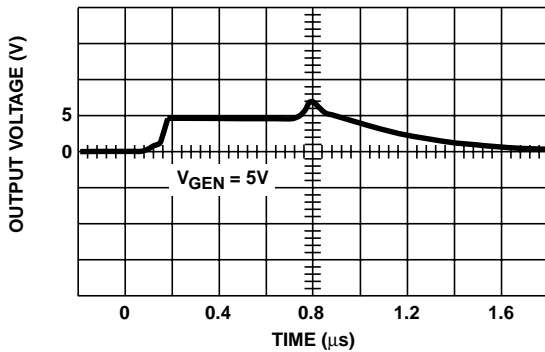


FIGURE 2E. $V_{ANALOG} = 5V$

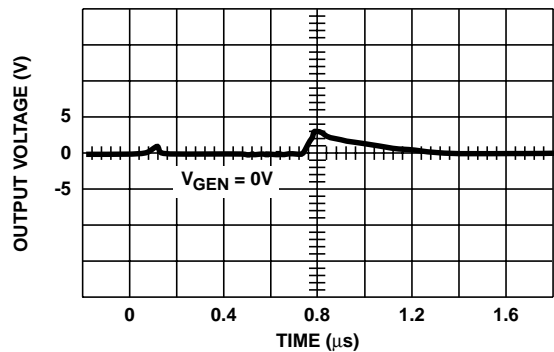


FIGURE 2F. $V_{ANALOG} = 0V$

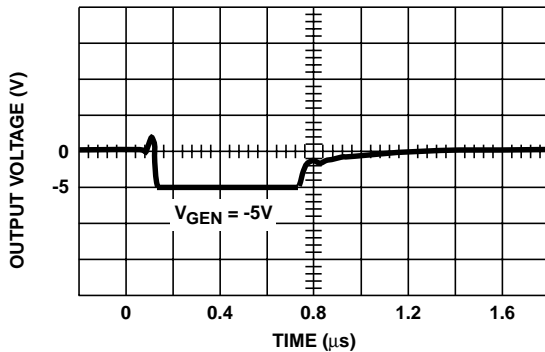


FIGURE 2G. $V_{ANALOG} = -5V$

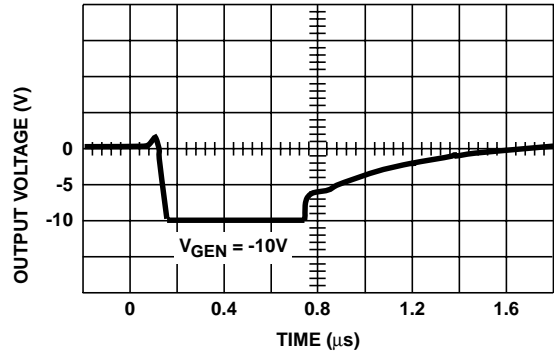


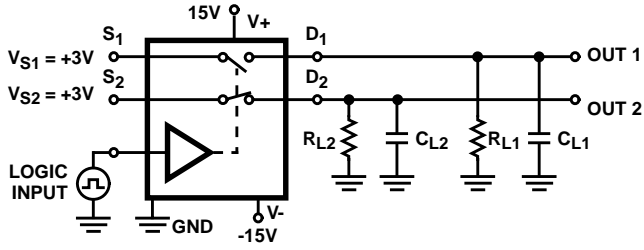
FIGURE 2H. $V_{ANALOG} = -10V$

NOTE:

16. If R_{GEN} , R_L or C_L is increased, there will be proportional increases in rise and/or fall RC times.

FIGURE 2. SWITCHING WAVEFORMS FOR VARIOUS ANALOG INPUT VOLTAGES

Test Circuits and Waveforms (Continued)



SWITCH TYPE	V _{INH}
HI-301, HI-303	5V
HI-307	15V

FIGURE 3A. TEST CIRCUIT

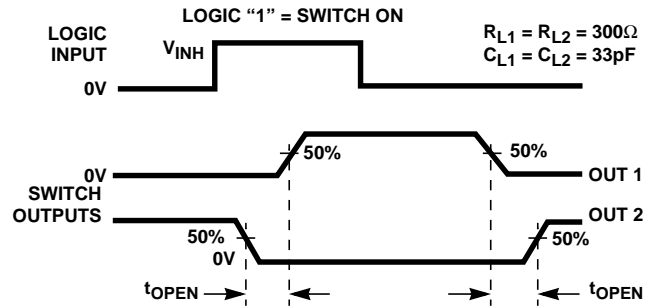


FIGURE 3B. MEASUREMENT POINTS

FIGURE 3. BREAK-BEFORE-MAKE DELAY (t_{OPEN})

Typical Performance Curves

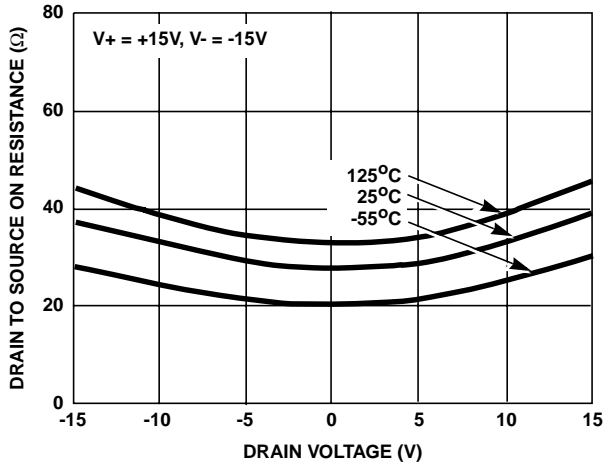


FIGURE 4. r_{DS(ON)} vs V_D

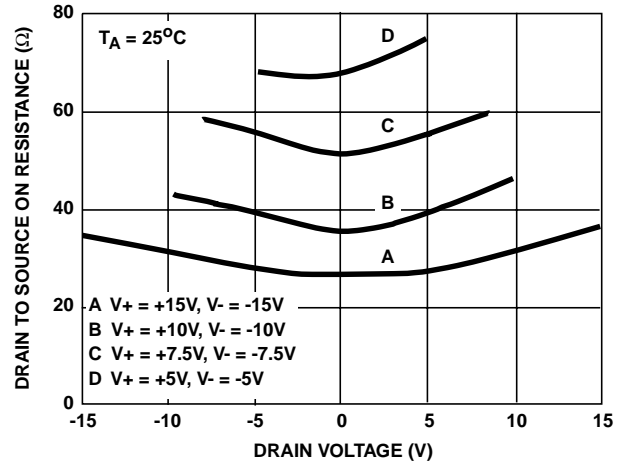


FIGURE 5. r_{DS(ON)} vs V_D

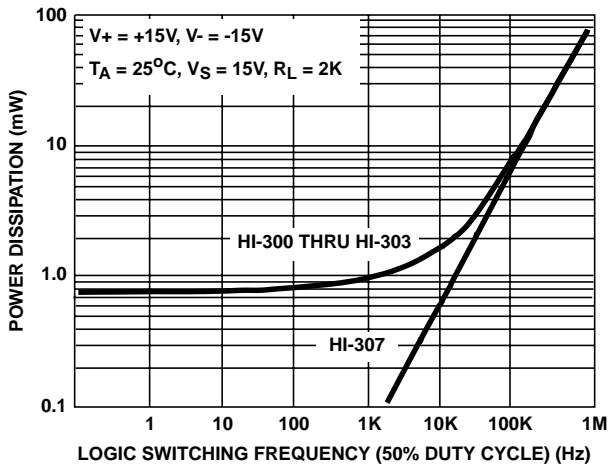


FIGURE 6. DEVICE POWER DISSIPATION vs SWITCHING FREQUENCY (SINGLE LOGIC INPUT)

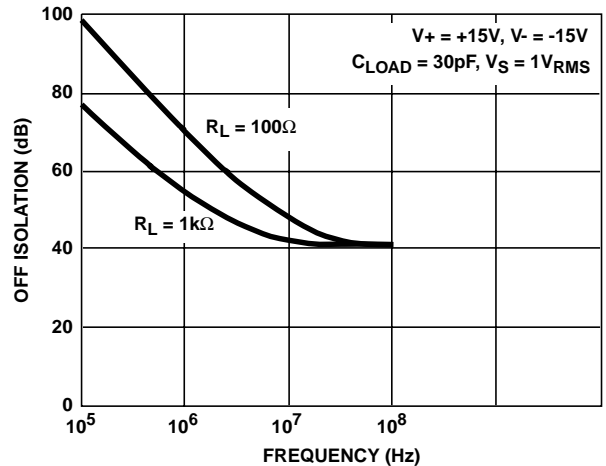


FIGURE 7. OFF ISOLATION vs FREQUENCY

Typical Performance Curves (Continued)

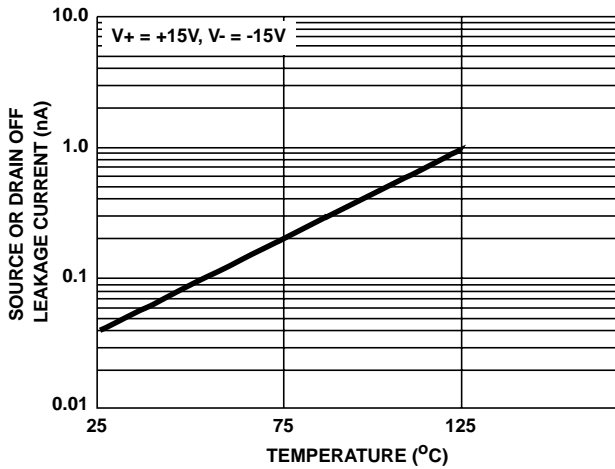


FIGURE 8. $I_{S(OFF)}$ OR $I_{D(OFF)}$ vs TEMPERATURE †

† The net leakage into the source or drain is the N-Channel leakage minus the P-Channel leakage. This difference can be positive, negative or zero depending on the analog voltage and temperature, and will vary greatly from unit to unit.

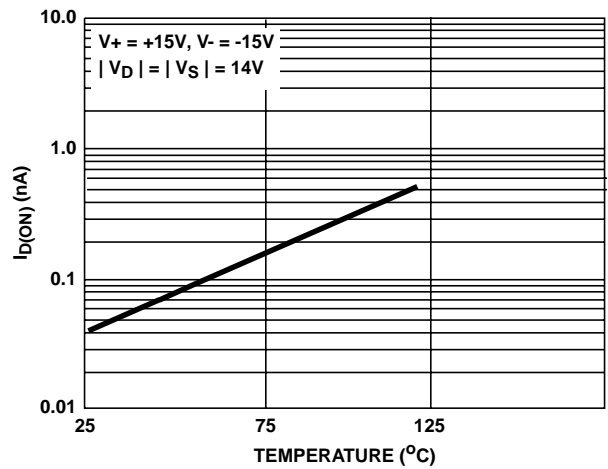


FIGURE 9. $I_{D(ON)}$ vs TEMPERATURE †

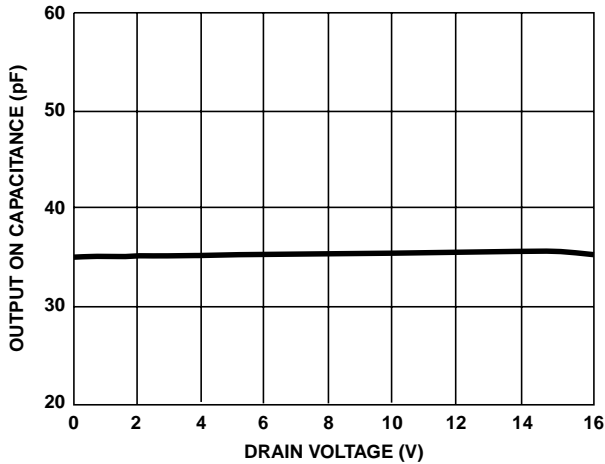


FIGURE 10. OUTPUT ON CAPACITANCE vs DRAIN VOLTAGE

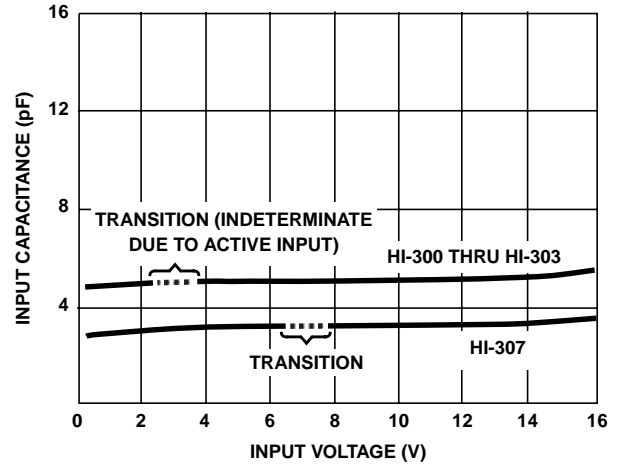


FIGURE 11. DIGITAL INPUT CAPACITANCE vs INPUT VOLTAGE

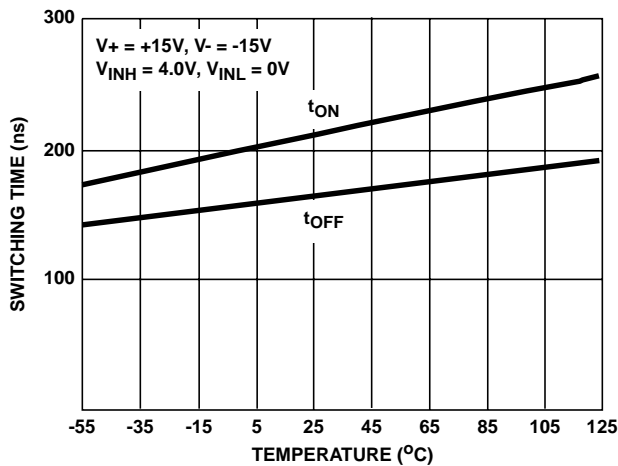


FIGURE 12. SWITCHING TIME vs TEMPERATURE, HI-300 THRU HI-303

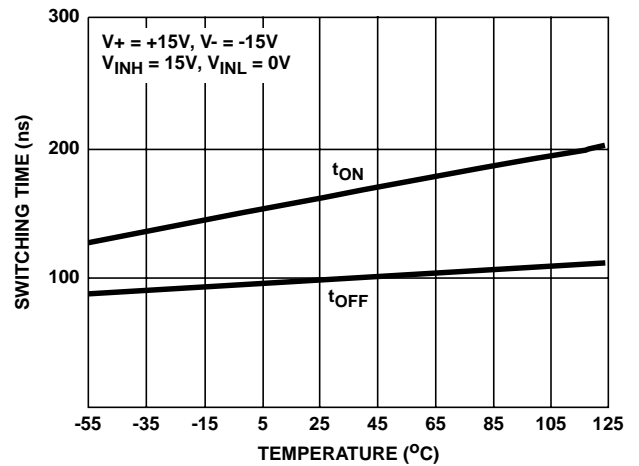


FIGURE 13. SWITCHING TIME vs TEMPERATURE, HI-307

Typical Performance Curves (Continued)

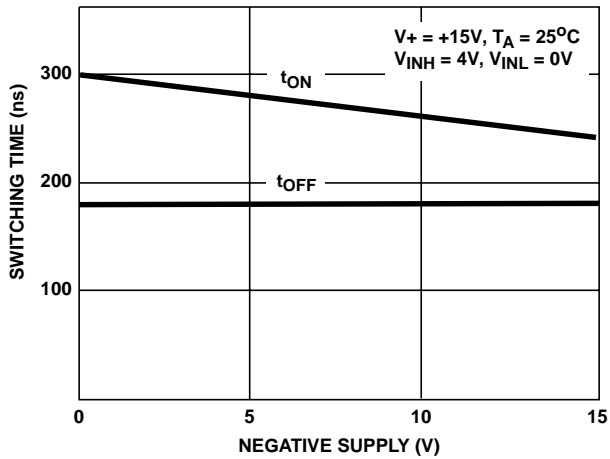


FIGURE 14. SWITCHING TIME vs NEGATIVE SUPPLY VOLTAGE, HI-300 THRU HI-303

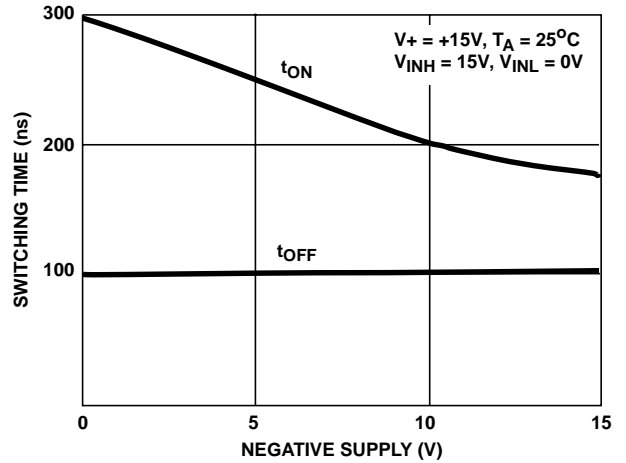


FIGURE 15. SWITCHING TIME vs NEGATIVE SUPPLY VOLTAGE, HI-307

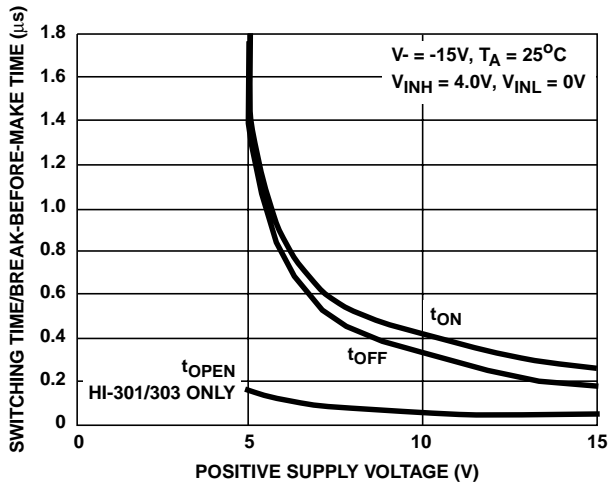


FIGURE 16. SWITCHING TIME AND BREAK-BEFORE-MAKE TIME vs POSITIVE SUPPLY VOLTAGE, HI-300 THRU HI-303

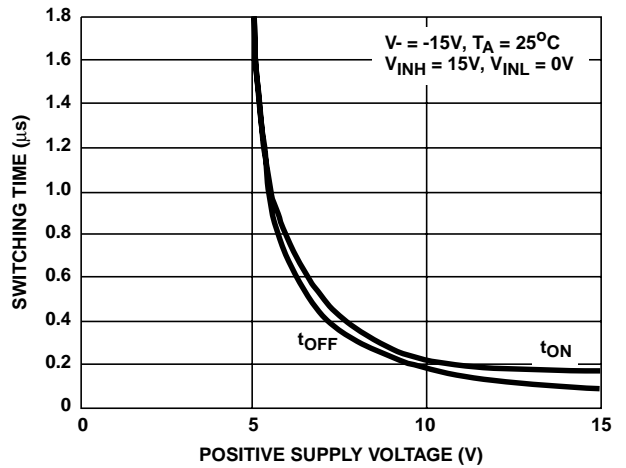


FIGURE 17. SWITCHING TIME vs POSITIVE SUPPLY VOLTAGE, HI-307

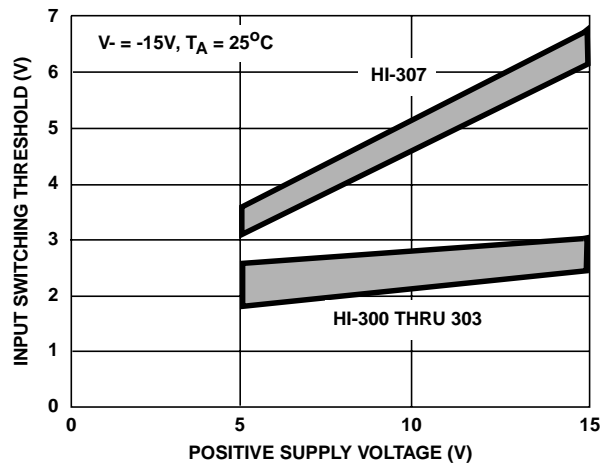


FIGURE 18. INPUT SWITCHING THRESHOLD vs POSITIVE SUPPLY VOLTAGE